



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: I0804-01 Product Affected: See attached list Date Effective: 18-Jul-2008	DATE: 18-Apr-2008	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark <input checked="" type="checkbox"/> Date Code Top mark ZC0828 and later <input type="checkbox"/> Other
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Contact: Bimla Paul Title: Quality Assurance Manager Phone #: (408)574-6419 Fax #: (408) 284-8362 E-mail: Bimla.Paul@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: N/A
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DESCRIPTION AND PURPOSE OF CHANGE:

Die Technology
 Wafer Fabrication Process
 Assembly Process Minor mask change to enhance yield
 Equipment
 Material There is no change to process and technology.
 Testing
 Manufacturing Site
 Data Sheet
 Other

RELIABILITY/QUALIFICATION SUMMARY:

See attached qual data. There is no change to die technology/process.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> Approval for shipments prior to effective date.
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT I - PCN # : I0804-01

PCN Type: Yield Enhancement
Data Sheet Change: No
Detail Of Change: Minor mask change to improve manufacturing yield.

On Part Ordering Information Page

There is no change to Part Ordering Information

Affected P/N

89HPES12N3AZCBC	89HPES24T6ZCDBX
89HPES12N3AZCBCG	89HPES24T6ZCBXG
89HPES24N3AZCBX	
89HPES24N3AZCBXG	

These changes affect all speed grades and package options. There is no change in die technology/process.



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ATTACHMENT I - PCN # : I0804-01

Qualification Information and Qualification Data:

Test Vehicle: IDT89HPES24N3A

Qualification Test Plan and Results:

Test Description	Sample Size/# Of Fails	Test Results (SS/# Of Fails)
Dynamic High Temp Operating Life Test	77/0	**77/0
* Temperature Cycling (-65 °C to 150 °C, 500 cycle)	45/0	**45/0
* Highly Accelerated Stress Test (HAST) (130 °C,85% RH, 100 Hrs)	45/0	**45/0
ESD HBM	3/0	**3/0
ESD CDM	3/0	**3/0

Notes: * Test requires Moisture Pre-Conditioning sequence.

** Data from prior qualification testing